

Notice of References Cited	Application/Control No. 10/676,294	Applicant(s)/Patent Under Reexamination GOLZARIAN ET AL.	
	Examiner Thanh V. Pham	Art Unit 2823	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-2004/0057191	03-2004	Timonov et al.	361/302
	C	US-4,233,671	11-1980	Gerzberg et al.	365/105
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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	V	Ruschau et al., "Percolation Constraints in the Use of Conductor-Filled Polymers for Interconnects", 1992 IEEE, pp 481-486.
	W	Yi-Li et al., "Electrical Property of Anisotropically Conductive Adhesive Joints Modified by Self-Assembled Monolayer (SAM)", 54th Electronic Components and Technology Conference, Vol. 2, Las Vegas, NV, USA, 1-4 June 2004.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.